

FIG. 3

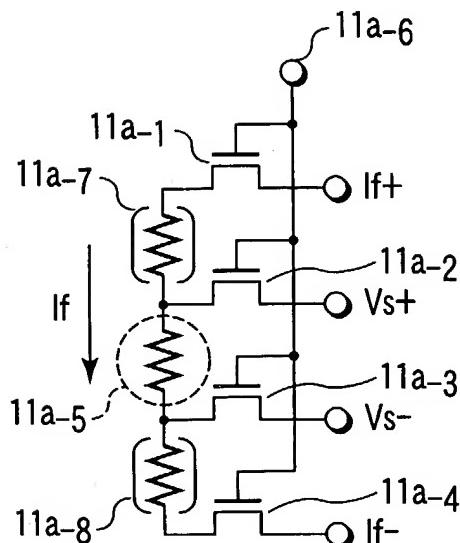


FIG. 4A

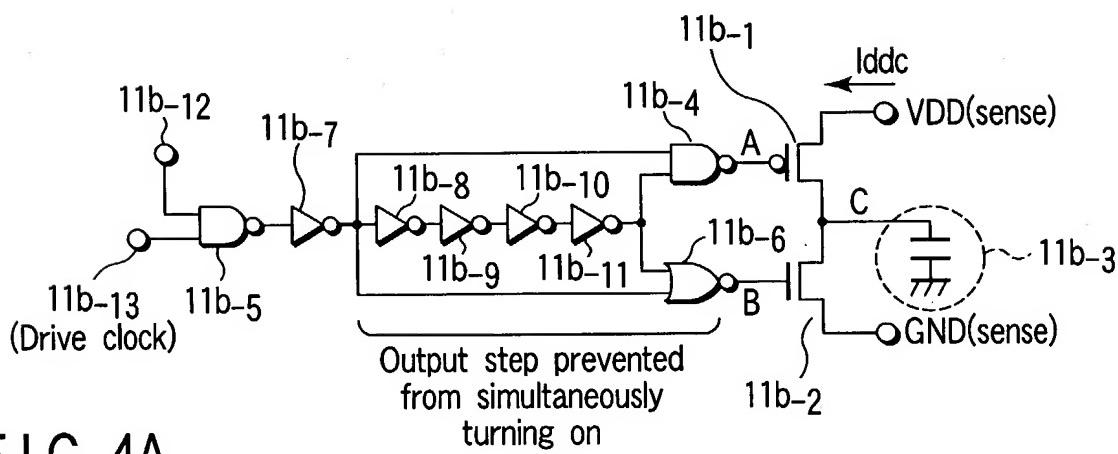
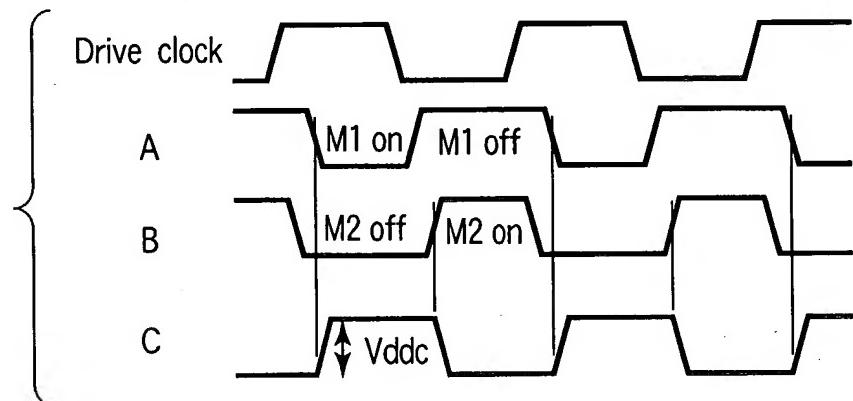
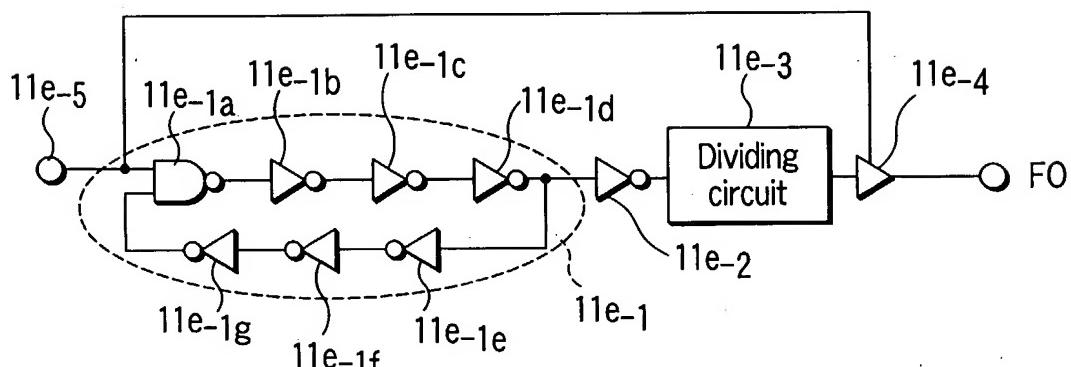
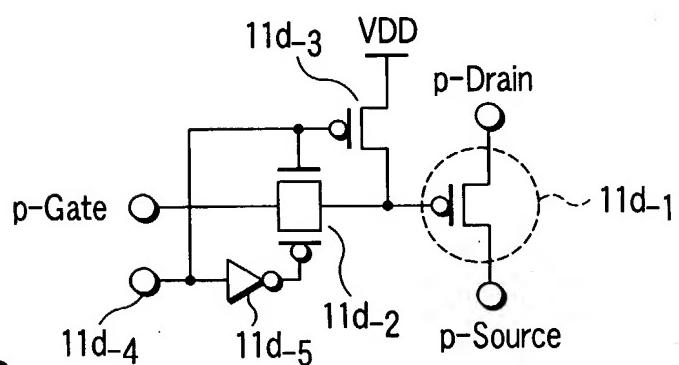
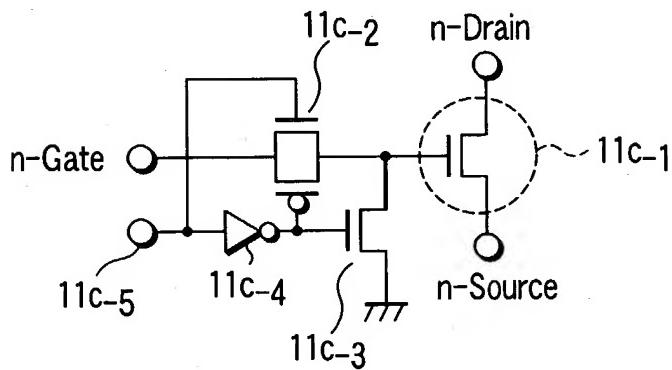


FIG. 4B





Title: SEMICONDUCTOR CHARACTERISTIC EVALUATION APPARATUS
Inventors: S. Ohkawa et al.
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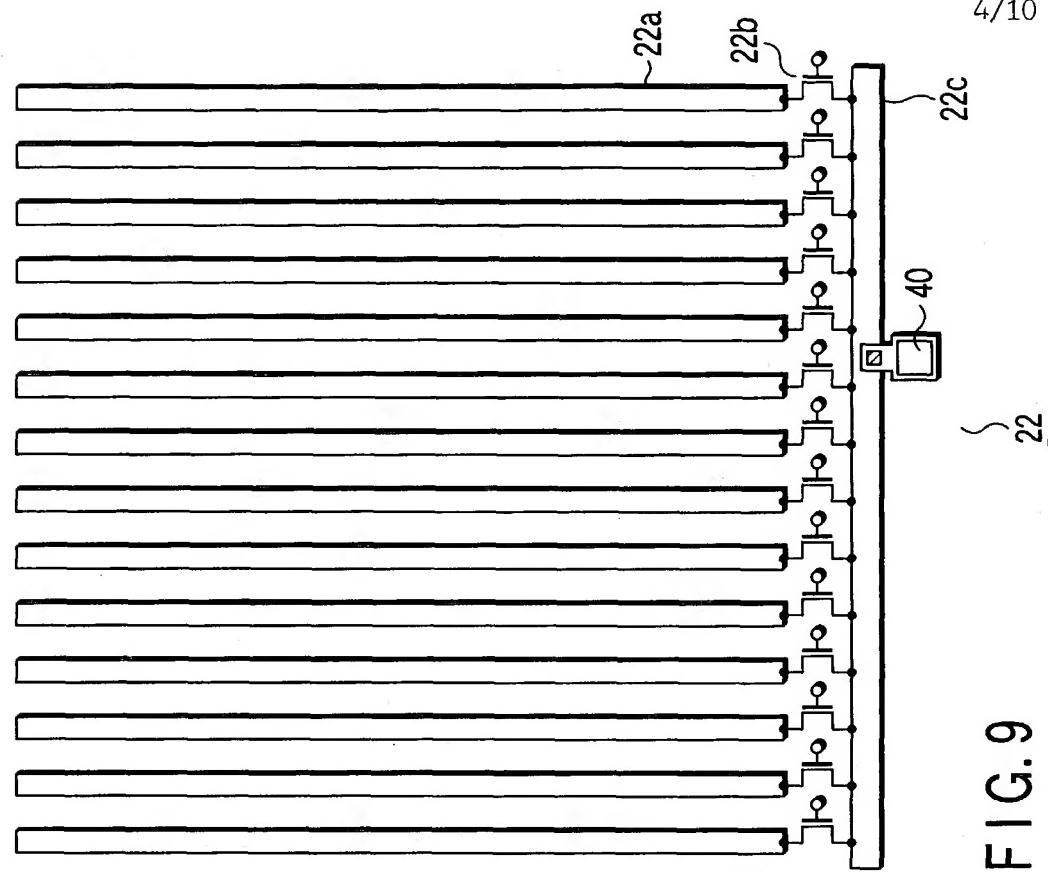


FIG. 9

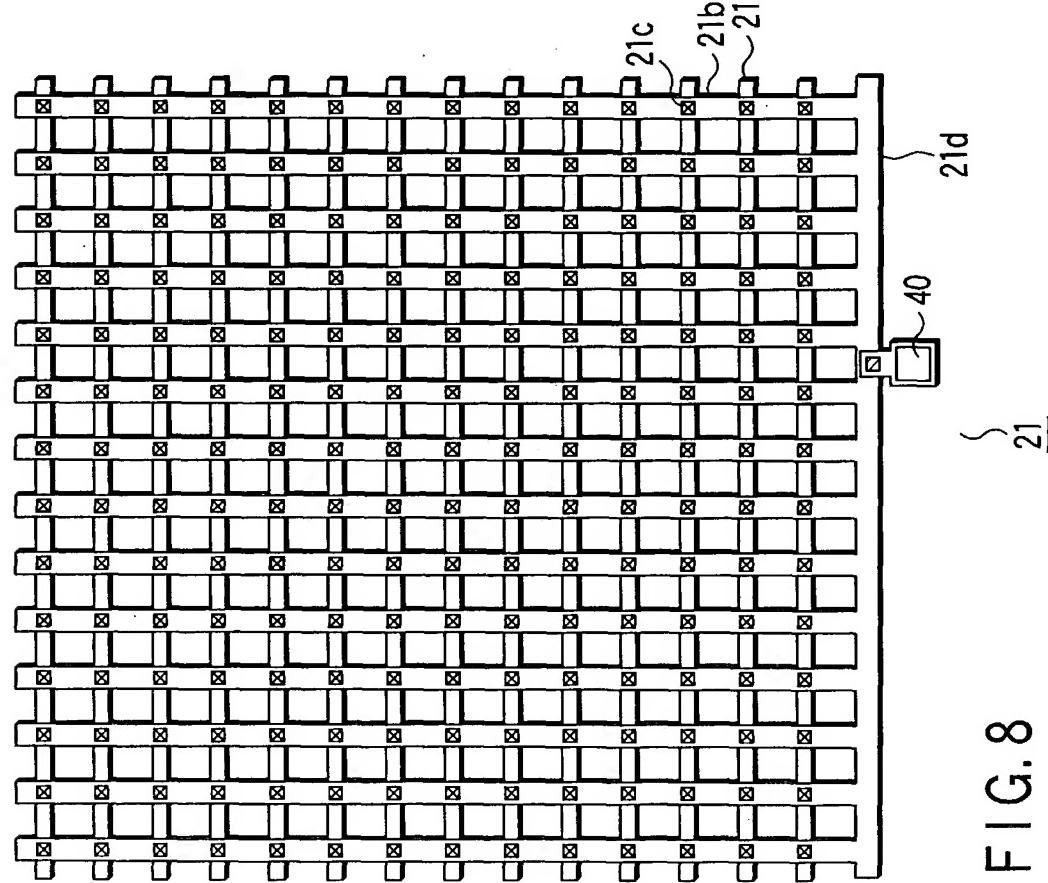


FIG. 8

Title: SEMICONDUCTOR CHARACTERISTIC EVALUATION APPARATUS
Inventors: S. Ohkawa et al.
Docket No.: SUSU121258

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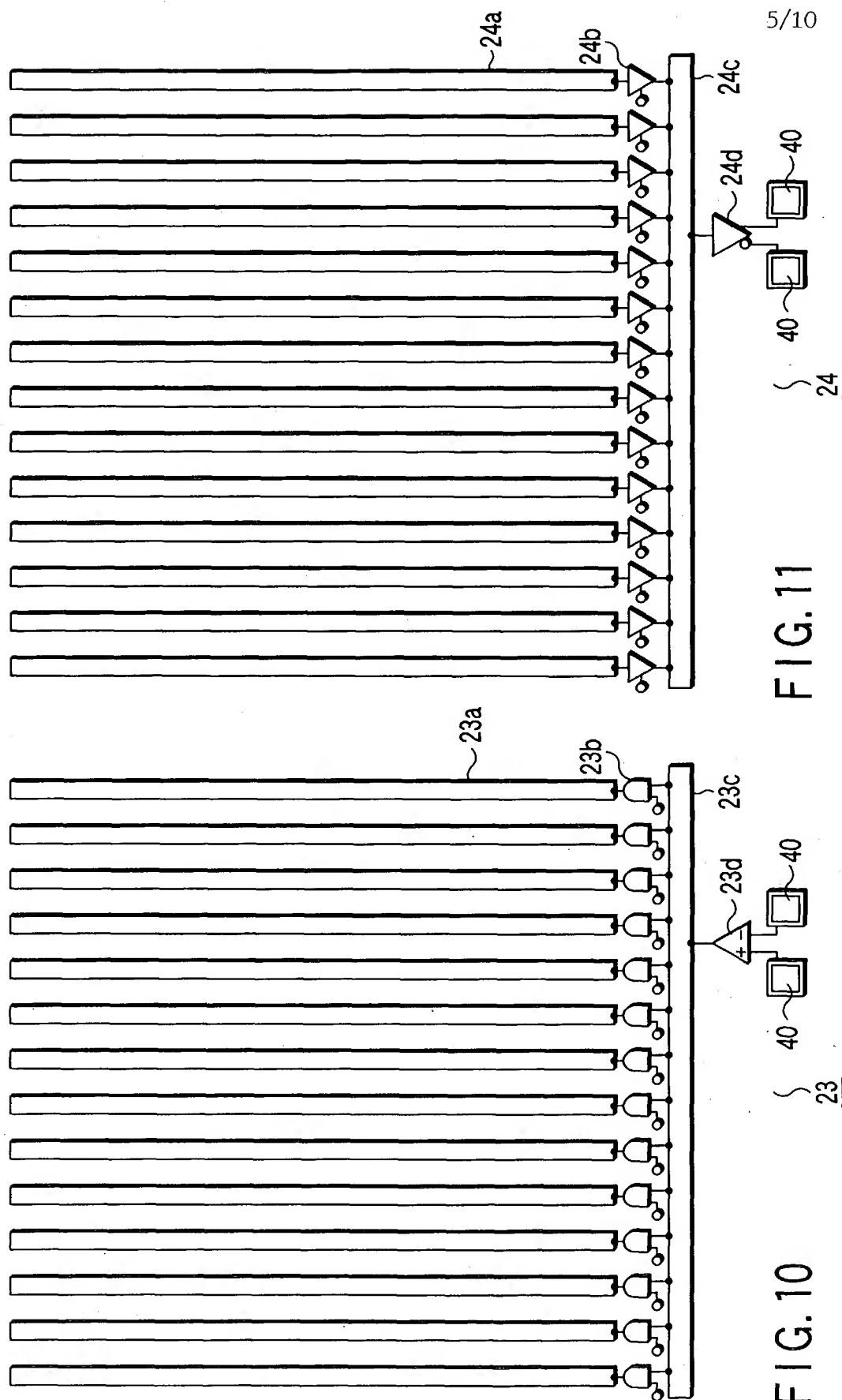


FIG. 11

FIG. 10

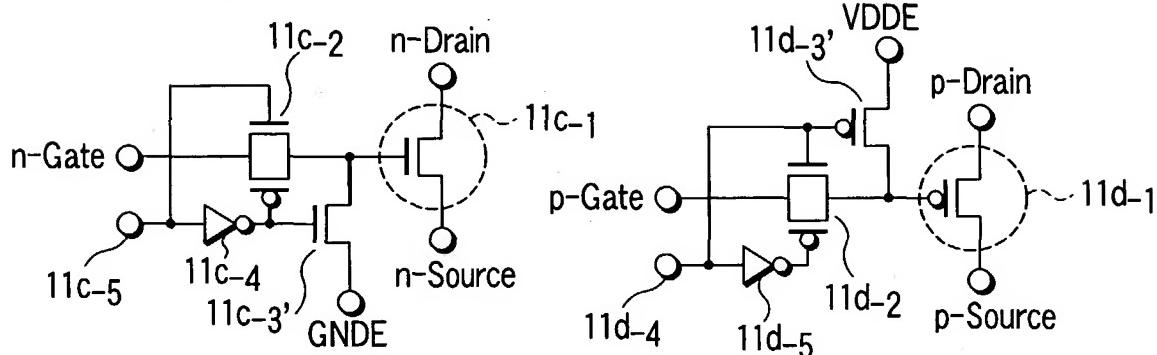


FIG. 12

FIG. 13

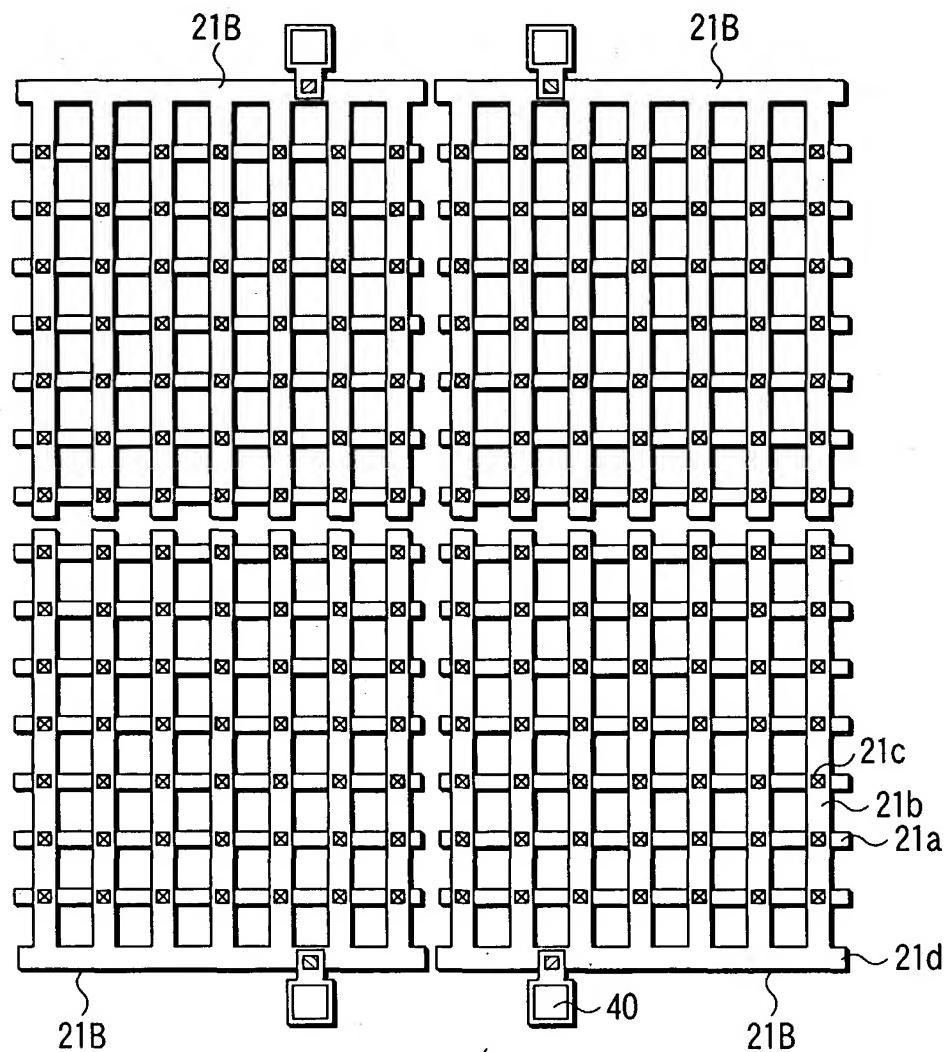


FIG. 14

21A

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Docket No.: SUSU121258

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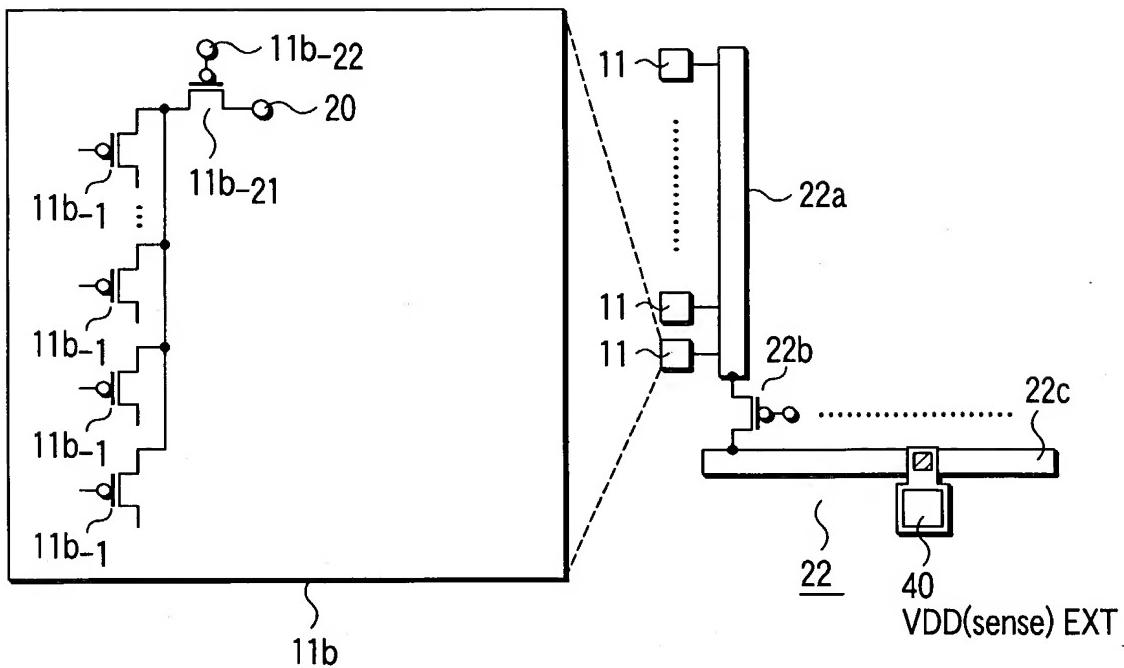


FIG. 15

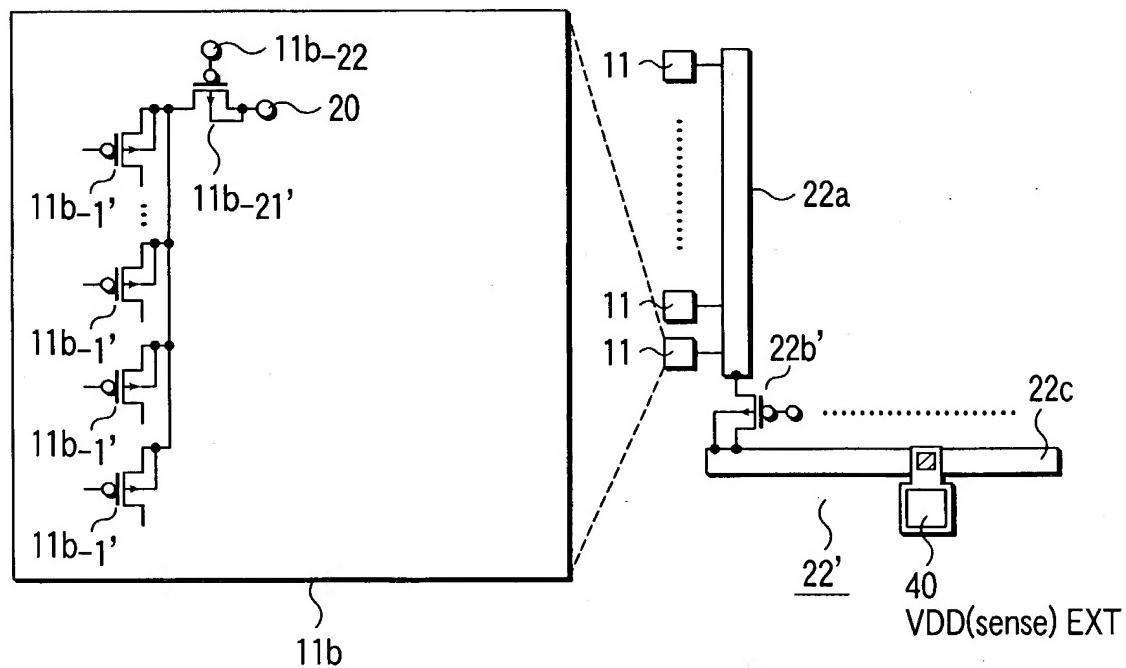


FIG. 16

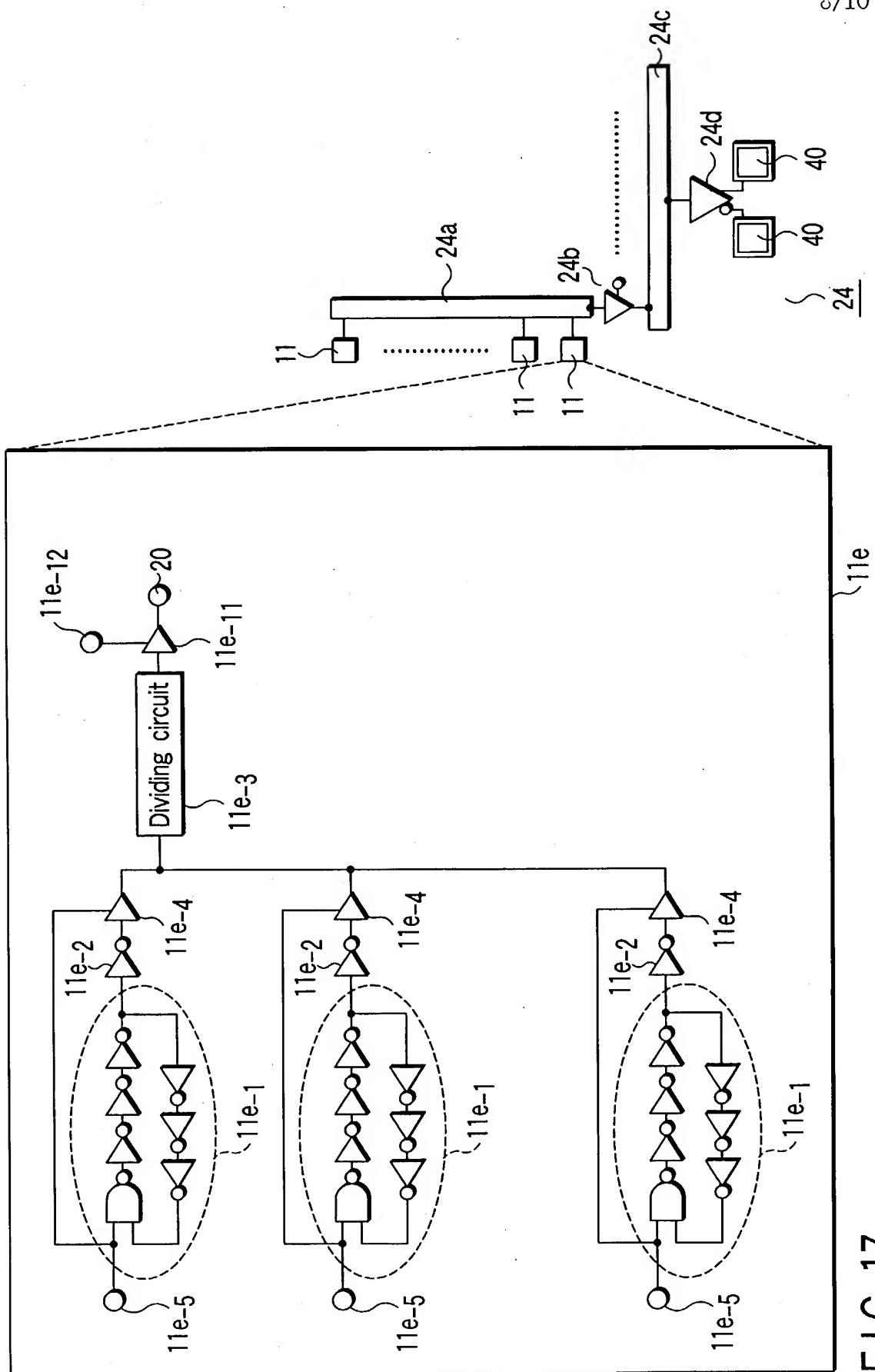


FIG. 17

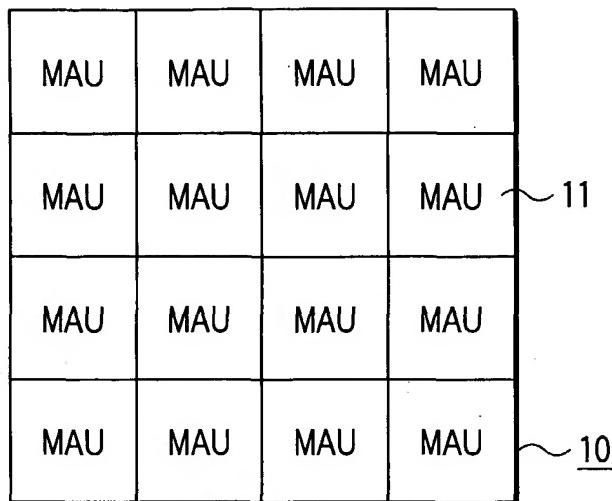


FIG. 18A

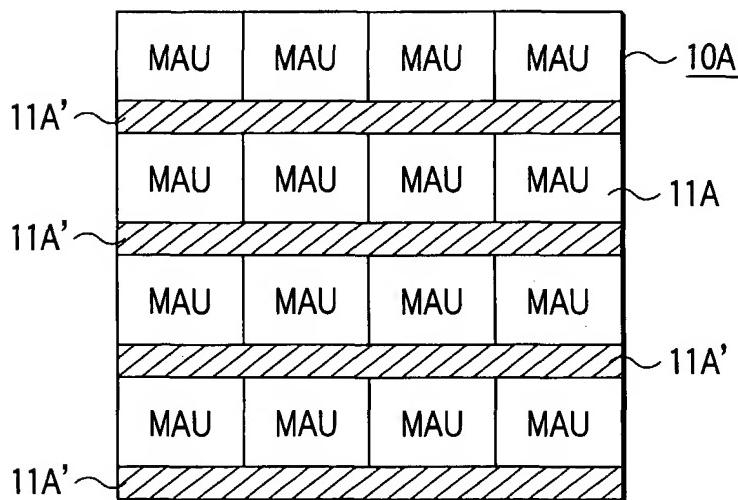


FIG. 18B

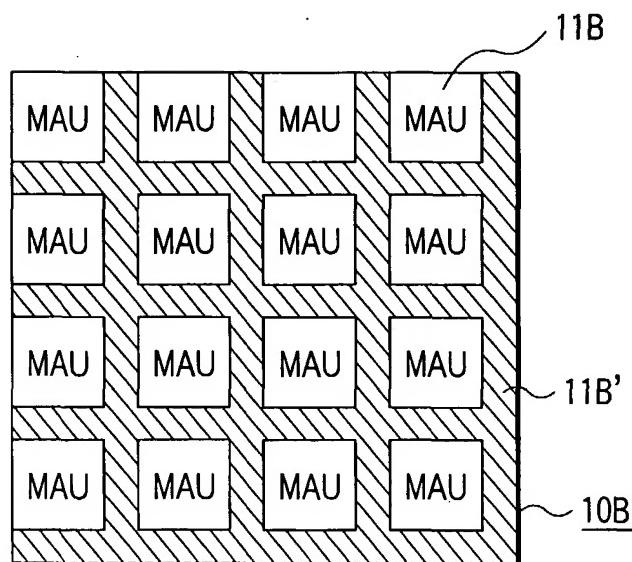


FIG. 18C

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Inventors: S. Ohkawa et al.
Docket No.: SUSU121258

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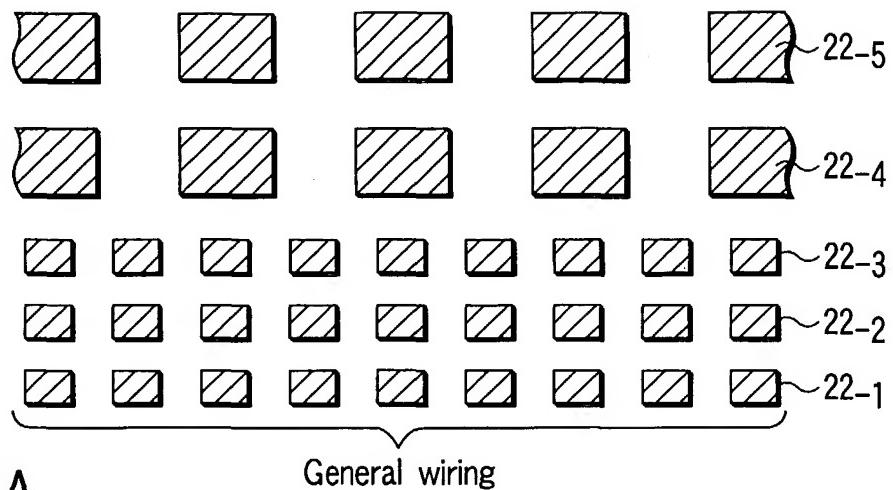


FIG. 19A

General wiring

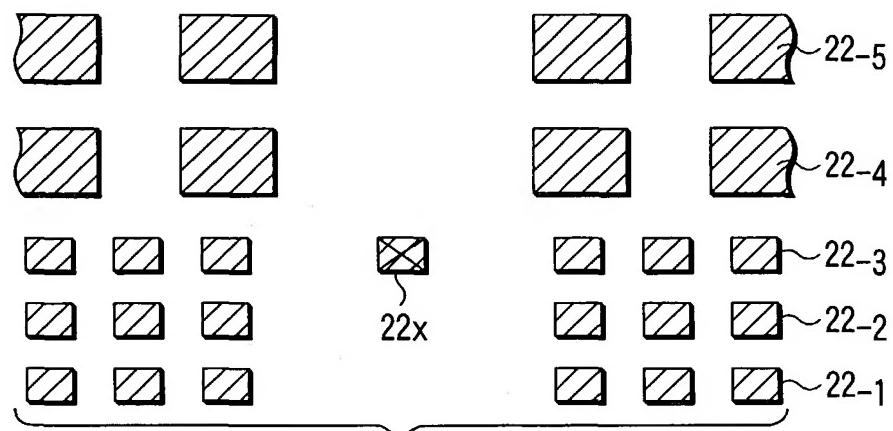


FIG. 19B

Low capacity wiring

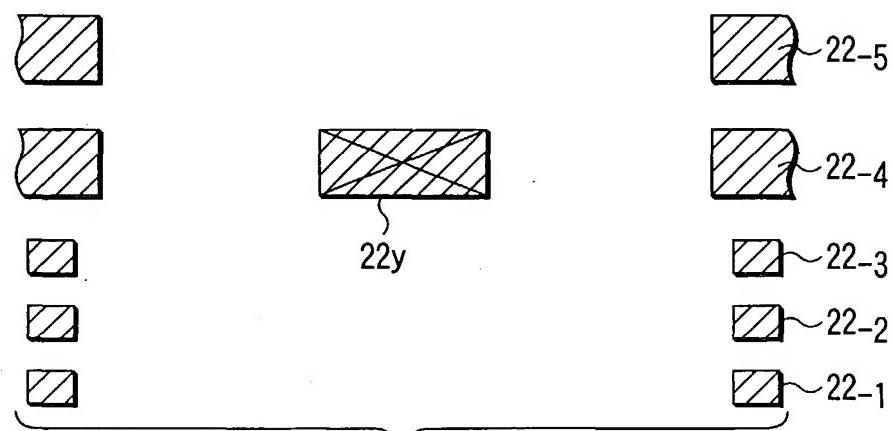


FIG. 19C

Low capacity and low resistance wiring